Notice	of References	Cited
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Application/Control No. 10/576,055	Applicant(s)/Pater Reexamination TANAKA ET AL.	nt Under
Examiner	Art Unit	
DAVID YI	2441	Page 1 of 1

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2003/0081595	05-2003	Nomura et al.	370/353
*	В	US-2003/0187746	10-2003	Kochanski, Gregory P.	705/26
*	С	US-7,082,456	07-2006	Mani-Meitav et al.	709/203
*	D	US-2002/0065035	05-2002	Koshino, Masayuki	455/3.01
	Е	US-			
	F	US-			
	G	US-		-	
	Н	US-		-	
	1	US-			
	J	US-			
	к	US-			
	٦	US-			
	м	US-			

## FOREIGN PATENT DOCUMENTS

FOREIGN PATENT DOCUMENTS						
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	N					
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	Q		l			
	R					
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NON-PATENT DOCUMENTS		
*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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